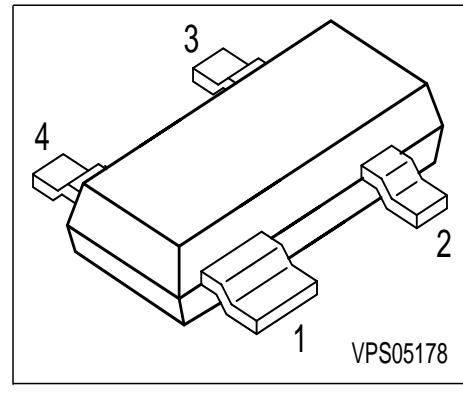
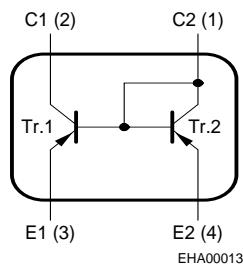


## PNP Silicon Double Transistor

- To be used as a current mirror
- Good thermal coupling and  $V_{BE}$  matching
- High current gain
- Low collector-emitter saturation voltage



Type	Marking	Pin Configuration				Package
BCV62A	3Js	1 = C2	2 = C1	3 = E1	4 = E2	SOT143
BCV62B	3Ks	1 = C2	2 = C1	3 = E1	4 = E2	SOT143
BCV62C	3Ls	1 = C2	2 = C1	3 = E1	4 = E2	SOT143

## Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage (transistor T1)	$V_{CEO}$	30	V
Collector-base voltage (open emitter) (transistor T1)	$V_{CBO}$	30	
Emitter-base voltage	$V_{EBS}$	6	
DC collector current	$I_C$	100	mA
Peak collector current	$I_{CM}$	200	
Base peak current (transistor T1)	$I_{BM}$	200	
Total power dissipation, $T_S = 99^\circ\text{C}$	$P_{tot}$	300	mW
Junction temperature	$T_J$	150	$^\circ\text{C}$
Storage temperature	$T_{stg}$	-65 ... 150	

## Thermal Resistance

Junction - soldering point <sup>1</sup> )	$R_{thJS}$	$\leq 170$	K/W
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<sup>1</sup>For calculation of  $R_{thJA}$  please refer to Application Note Thermal Resistance

**Electrical Characteristics** at  $T_A = 25^\circ\text{C}$ , unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
<b>DC Characteristics of T1</b>					
Collector-emitter breakdown voltage $I_C = 10 \text{ mA}, I_B = 0$	$V_{(\text{BR})\text{CEO}}$	30	-	-	V
Collector-base breakdown voltage $I_C = 10 \mu\text{A}, I_B = 0$	$V_{(\text{BR})\text{CBO}}$	30	-	-	
Emitter-base breakdown voltage $I_E = 10 \mu\text{A}, I_C = 0$	$V_{(\text{BR})\text{EBO}}$	6	-	-	
Collector cutoff current $V_{\text{CB}} = 30 \text{ V}, I_E = 0$	$I_{\text{CBO}}$	-	-	15	nA
Collector cutoff current $V_{\text{CB}} = 30 \text{ V}, I_E = 0, T_A = 150^\circ\text{C}$	$I_{\text{CBO}}$	-	-	5	µA
DC current gain 1) $I_C = 0.1 \text{ mA}, V_{\text{CE}} = 5 \text{ V}$	$h_{\text{FE}}$	100	-	-	-
DC current gain 1) $I_C = 2 \text{ mA}, V_{\text{CE}} = 5 \text{ V}$		125	180	220	
		220	290	475	
		420	520	800	
Collector-emitter saturation voltage1) $I_C = 10 \text{ mA}, I_B = 0.5 \text{ mA}$ $I_C = 100 \text{ mA}, I_B = 5 \text{ mA}$	$V_{\text{CEsat}}$	-	75	300	mV
Base-emitter saturation voltage 1) $I_C = 10 \text{ mA}, I_B = 0.5 \text{ mA}$ $I_C = 100 \text{ mA}, I_B = 5 \text{ mA}$		-	250	650	
		-	700	-	
		-	850	-	
Base-emitter voltage 1) $I_C = 2 \text{ mA}, V_{\text{CE}} = 5 \text{ V}$ $I_C = 10 \text{ mA}, V_{\text{CE}} = 5 \text{ V}$	$V_{\text{BE}(\text{ON})}$	600	650	750	
		-	-	820	

1) Pulse test:  $t \leq 300 \mu\text{s}$ ,  $D = 2\%$

**Electrical Characteristics** at  $T_A = 25^\circ\text{C}$ , unless otherwise specified.

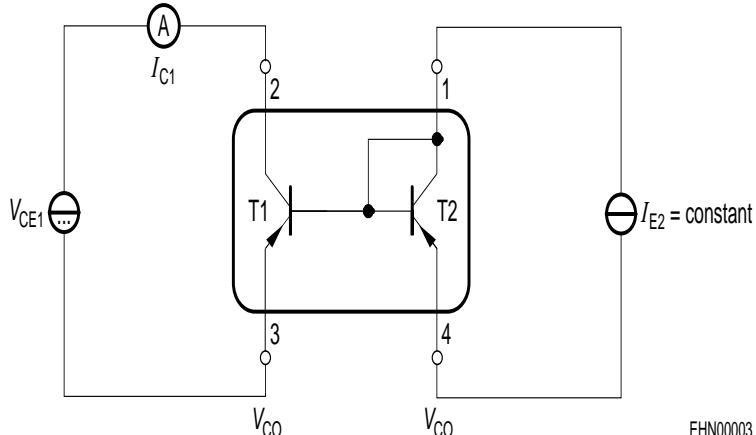
Parameter	Symbol	Values			Unit
		min.	typ.	max.	
<b>DC Characteristics</b>					
Base-emitter forward voltage $I_E = 10 \mu\text{A}$	$V_{BES}$	0.4	-	-	V
$I_E = 250 \text{ mA}$		-	-	1.8	
Matching of transistor T1 and transistor T2 at $I_{E2} = 0.5 \text{ mA}$ and $V_{CE1} = 5 \text{ V}$ $T_A = 25^\circ\text{C}$ $T_A = 150^\circ\text{C}$	$I_{C1} / I_{C2}$	-	-	-	-
		0.7	-	1.3	
		0.7	-	1.3	
Thermal coupling of transistor T1 and transistor T2 <sup>1)</sup> T1: $V_{CE} = 5 \text{ V}$ Maximum current of thermal stability of $I_{C1}$	$I_{E2}$	-	5	-	mA

#### AC characteristics of transistor T1

Transition frequency $I_C = 10 \text{ mA}, V_{CE} = 5 \text{ V}, f = 100 \text{ MHz}$	$f_T$	-	250	-	MHz
Collector-base capacitance $V_{CB} = 10 \text{ V}, f = 1 \text{ MHz}$	$C_{cb}$	-	3	-	pF
Emitter-base capacitance $V_{EB} = 0.5 \text{ V}, f = 1 \text{ MHz}$	$C_{eb}$	-	8	-	
Noise figure $I_C = 200 \mu\text{A}, V_{CE} = 5 \text{ V}, R_S = 2 \text{ k}\Omega, f = 1 \text{ kHz}, \Delta f = 200 \text{ Hz}$	$F$	-	2	-	dB
Short-circuit input impedance $I_C = 1 \text{ mA}, V_{CE} = 10 \text{ V}, f = 1 \text{ kHz}$	$h_{11e}$	-	4.5	-	k $\Omega$
Open-circuit reverse voltage transf.ratio $I_C = 1 \text{ mA}, V_{CE} = 10 \text{ V}, f = 1 \text{ kHz}$	$h_{12e}$	-	2	-	$10^{-4}$
Short-circuit forward current transf.ratio $I_C = 1 \text{ mA}, V_{CE} = 10 \text{ V}, f = 1 \text{ kHz}$	$h_{21e}$	100	-	900	-
Open-circuit output admittance $I_C = 1 \text{ mA}, V_{CE} = 10 \text{ V}, f = 1 \text{ kHz}$	$h_{22e}$	-	30	-	$\mu\text{S}$

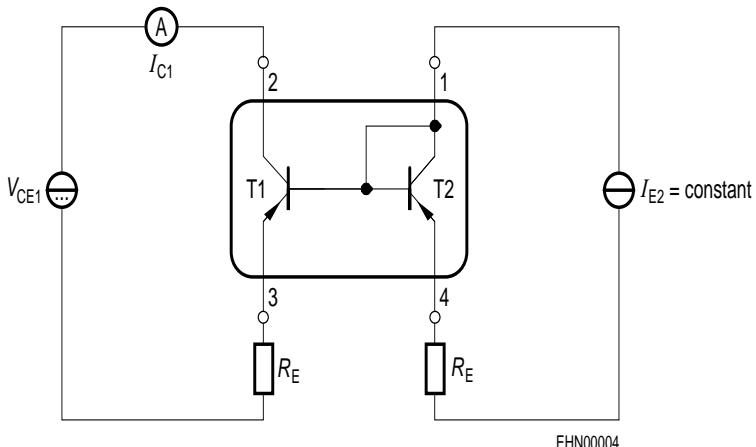
1) Without emitter resistor. Device mounted on alumina 15mm x 16.5mm x 0.7mm

### Test circuit for current matching



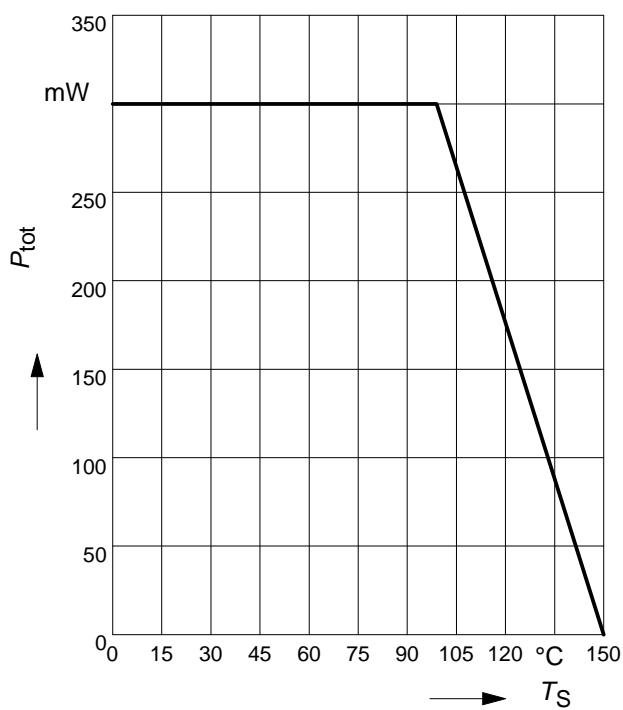
Note: Voltage drop at contacts:  $V_{CO} < 2/3 V_T = 16\text{mV}$

**Characteristic for determination of  $V_{CE1}$  at specified  $R_E$  range with  $I_{E2}$  as parameter under condition of  $I_{C1}/I_{E2} = 1.3$**



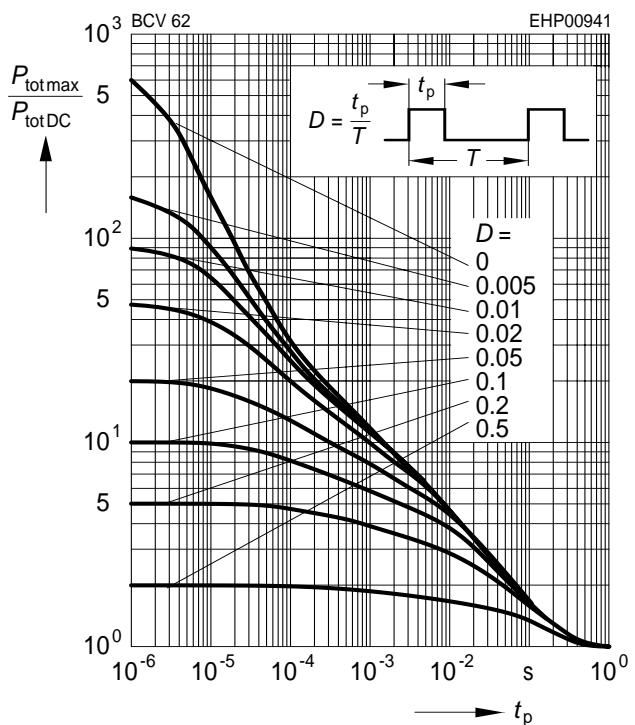
Note: BCV62 with emitter resistors

**Total power dissipation  $P_{\text{tot}} = f(T_S)$**

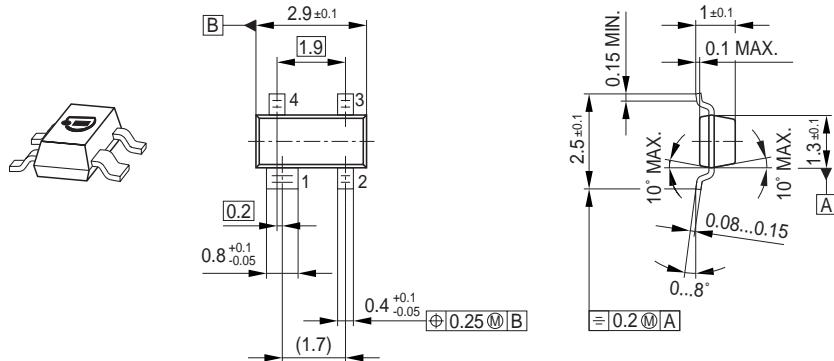


**Permissible pulse load**

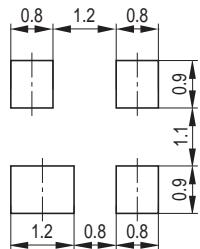
$$P_{\text{totmax}} / P_{\text{totDC}} = f(t_p)$$



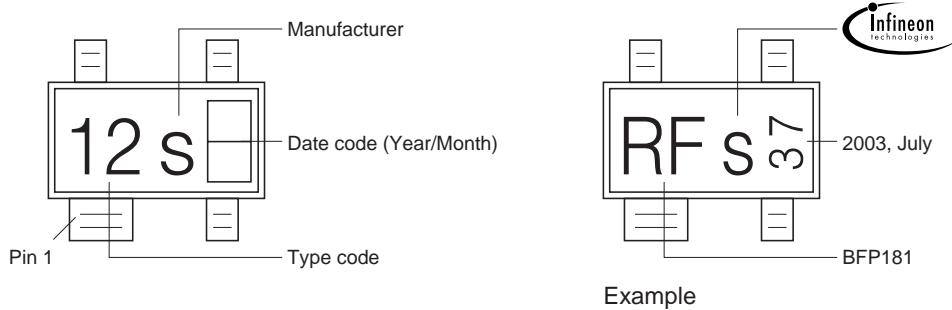
### Package Outline



### Foot Print



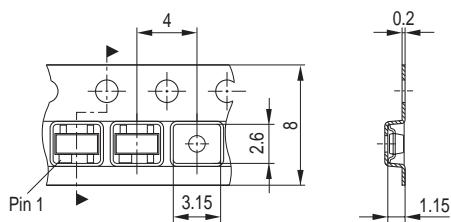
### Marking Layout



### Packing

Code E6327: Reel ø180 mm = 3.000 Pieces/Reel

Code E6433: Reel ø330 mm = 10.000 Pieces/Reel



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